

**MD.29.**

<b>Title</b>	<i>Device for measuring the parameters of a sensor based on nanostructured semiconductor oxides in the range of the order of microwatts</i>
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<b>Patent no.</b>	<b>MD 1270 Z 2018.07.31</b>
<b>Description</b>	The device for measuring the parameters of a sensor based on nanostructured semiconductor oxides in the range of the order of microwatts comprises an adjustable reference voltage source, connected in series to a test sensor and a standard resistance. The total voltage drops across the sensor and the standard resistance, and separately, the voltage drops across the standard resistance being applied to the inputs of two analog-to-digital converters of a microcontroller through two operational amplifiers. The outputs of the microcontroller are connected by a digital-to-analog converter to the input of the adjustable reference voltage source and to a screen for displaying the obtained results.
<b>EN</b>	
<b>Class no.</b>	<b>1. Environment - Pollution Control</b>